Docket No.

239499US2/hc

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yukio TANIGUCHI, et al.

OCT 2 1 200

SERIAL NO: 10/603,821

GAU:

FILED: June 26, 2003

EXAMINER:

FOR:

CRYSTALLIZATION APPARATUS, OPTICAL MEMBER FOR USE IN CRYSTALLIZATION APPARATUS, CRYSTALLIZATION METHOD, MANUFACTURING METHOD OF THIN FILM TRANSISTOR, AND

MANUFACTURING METHOD OF MATRIX CIRCUIT SUBSTRATE OF DISPLAY

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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STATEMENT OF RELEVANCY

Reference AY on Form 1449:

Fig. 4 illustrates a phenomenon wherein a laser beam undergoes phase modulation at the shifting portion of a phase shift mask, thereby inclining the wavefront.

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				APPLICANT				
LIST OF REFERENCES CITED BY APPLICANT				Yukio TANIGUCHI, et al.				
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	AW	EXCIMER-LASER CRYS	IALLIZA	s., vol. 37, Part 2, no. 5A, pages L492-L48 TION METHOD OF SILICON THIN FILM	,,	•		
	AX	PROCESS FOR QUASIS	SINGLE	id Films, vol. 337, pages 123-128, "ADVA CRYSTAL SILICON THIN-FILM DEVICE	• ,			
	AY	M. MATSUMURA, Applied WITH ULTRALARGE GR	d Physic AINS",	s, vol. 71, no. 5, pages 543-547, "EXCIM 2002	EK-LASE	N-GROWN	JILIOON	
	AZ				Additional References sheet(s) attach			
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